

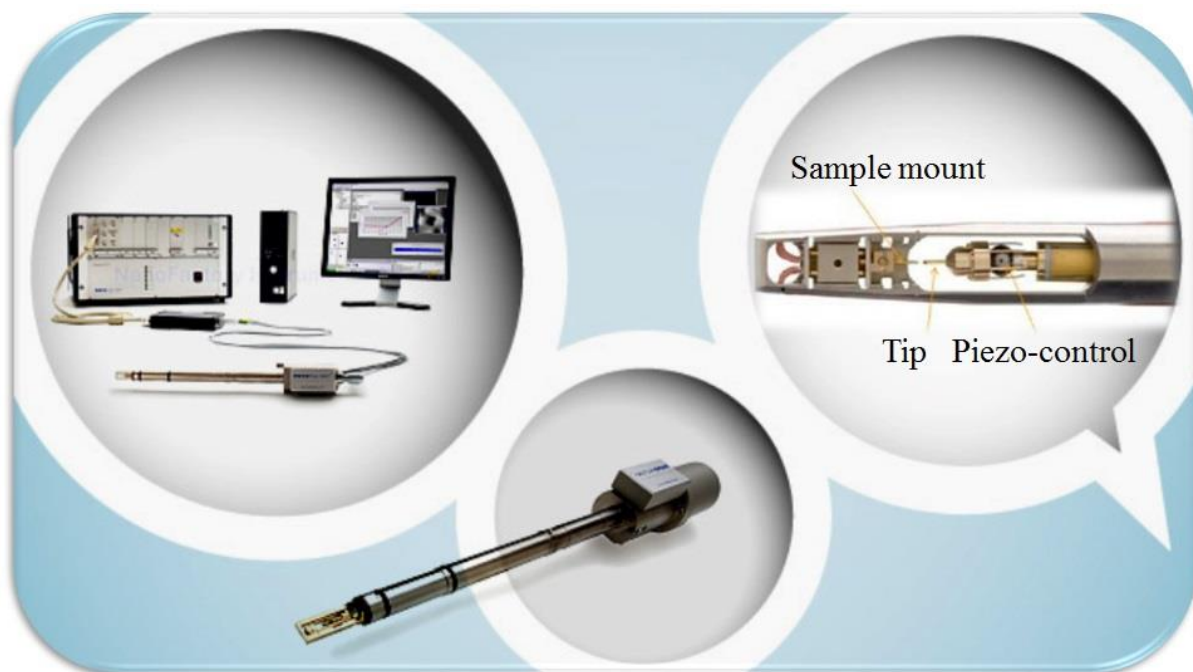
## UMF Equipment – Nanofactory STM Holder System

The Nanofactory STM holder system can be used to measure the electrical properties at specific locations of a nanostructure with sub-nanometer accuracy. The holder has a maximum current range of 0.5mA, a maximum bias of +/-10V and a max scanning range of 25 $\mu$ m $\times$ 25 $\mu$ m. It provides accurate uncoupled movements along the X, Y, and Z axes of motion, allowing for easy point-contact with the sample and high-resolution TEM imaging.

- Features:
- Mobile probe for electrical contacts
  - Probe's uncoupled coarse and fine movements along X, Y, and Z axes
  - Easy probe exchange
  - Removable sample cartridge
  - Intuitive graphical user interface

Please refer to the similar brand <http://www.zeptools.com/products/STM-TEM/2019/0927/1450.html> for further details of the system.

For any enquiry, please contact Dr. Wei Lu (Tel: 34002077; Email: [wei.lu@polyu.edu.hk](mailto:wei.lu@polyu.edu.hk)).



Application:

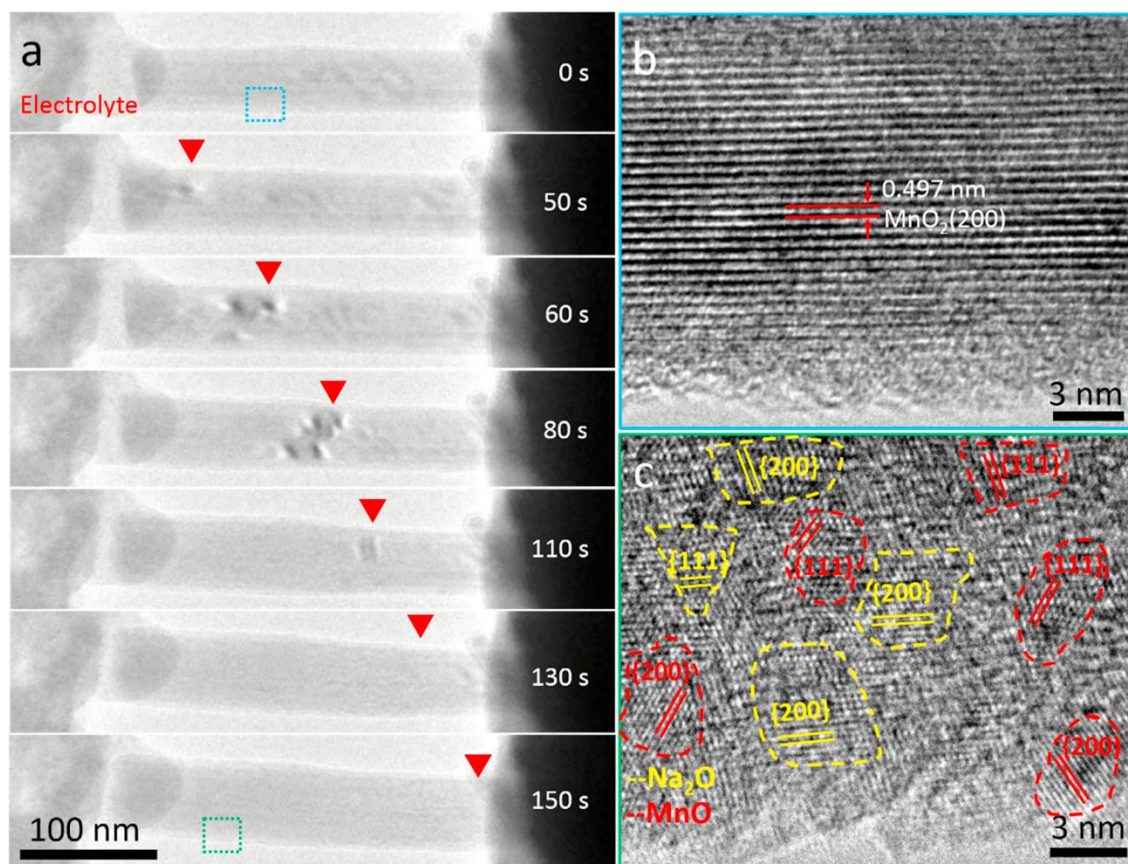
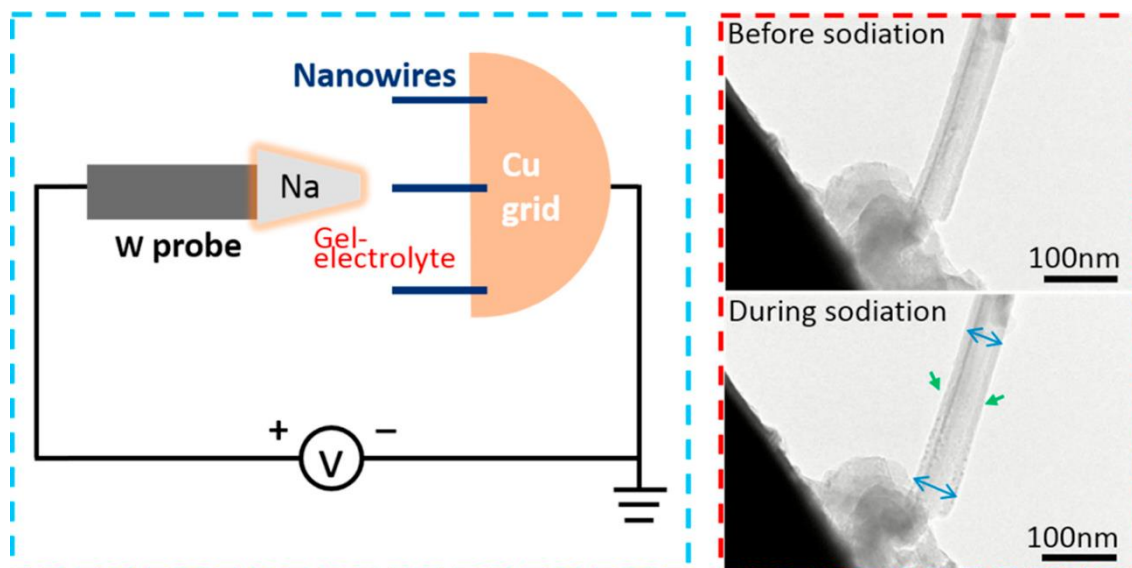


Fig. (a) A series of captured TEM images of a single MnO<sub>2</sub> nanowire showing the morphology and microstructure changes during sodiation process. (b, c) High-resolution TEM images of MnO<sub>2</sub> nanowire before and after sodiation process, respectively. (<https://doi.org/10.1016/j.ensm.2018.03.019>, Volume 15, November 2018, Pages 91-97, Energy Storage Materials)